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TENCON '93. Proceedings. Computer, Communication, Control and Power Engineering.1993 IEEE Region 10 Conference on , Issue: 0 , 19-21 Oct. 1993 Pages:357 - 360 vol.3

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2 DCT color image sequence coding*Rong-Jian Chen; Bin-Chang Chieu;*

Pattern Recognition, 1992. Vol.III. Conference C: Image, Speech and Signal Analysis, Proceedings., 11th IAPR International Conference on , 30 Aug.-3 Sep 1992 Pages:553 - 556

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 Image Processing, IEEE Transactions on , Volume: 7 , Issue: 6 , June 1998
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